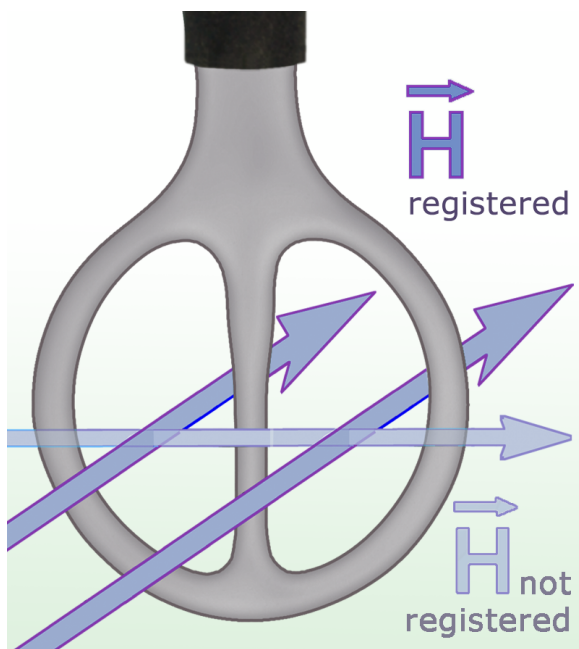


XF-R 400-1

H-Field Probe 30 MHz up to 6 GHz

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Short description

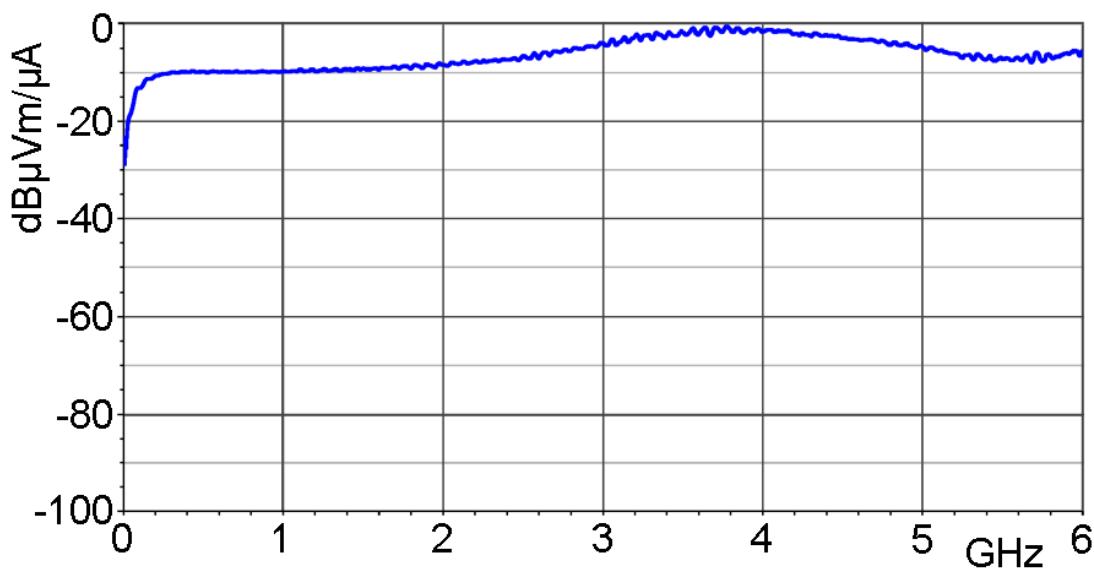
Due to its large diameter (25 mm) and its high resolution, the XF-R 400-1 H-field probe is suitable for measurements at distances up to 10 cm around assemblies and devices.

The XF-R 400-1 is a passive near-field probe. In principle it has the same structure as the XF-R 100-1 and XF-R 3-2 probes. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50Ω input. The H-field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 6 GHz
Probe head dimensions	$\varnothing \approx 25$ mm
Connector - output	SMA, female, jack
Weight	15 g

Frequency response [dB μ V] / [dB μ A/m]

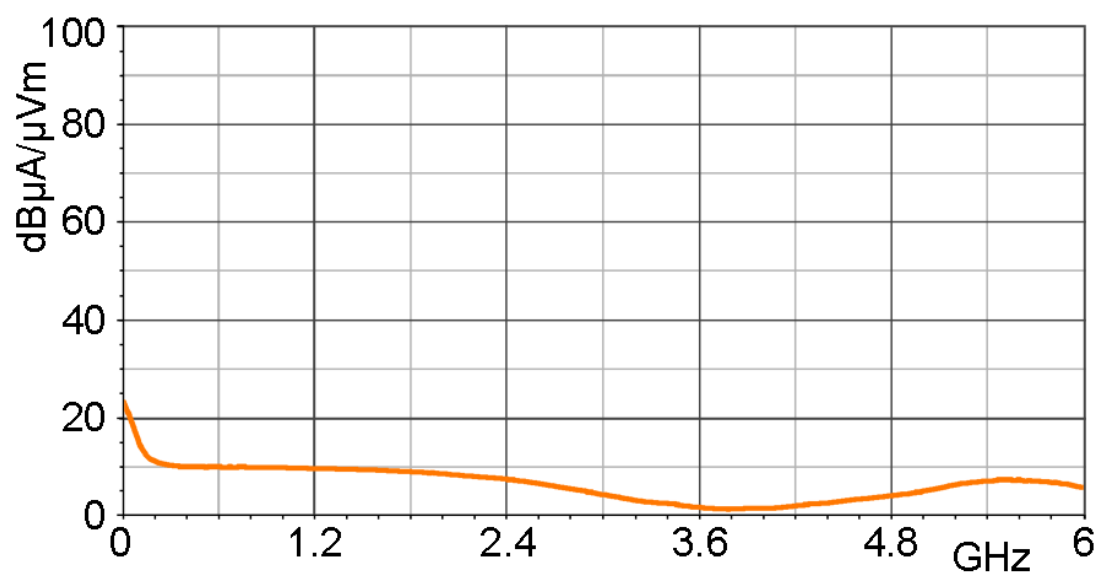


XF-R 400-1

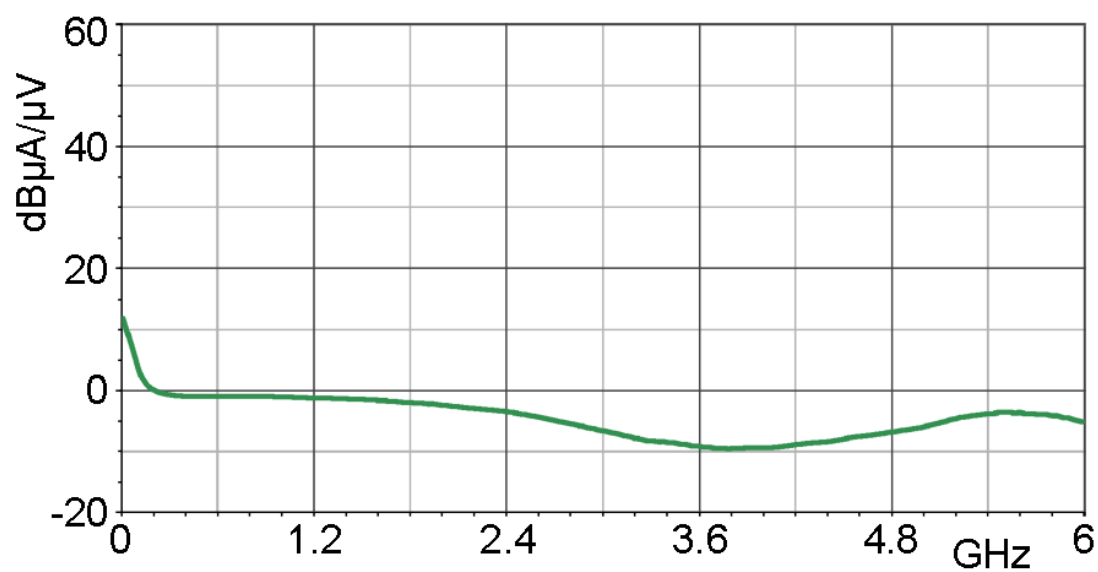
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H-field correction curve [dB μ A/m] / [dB μ V]



Current correction curve [dB μ A] / [dB μ V]

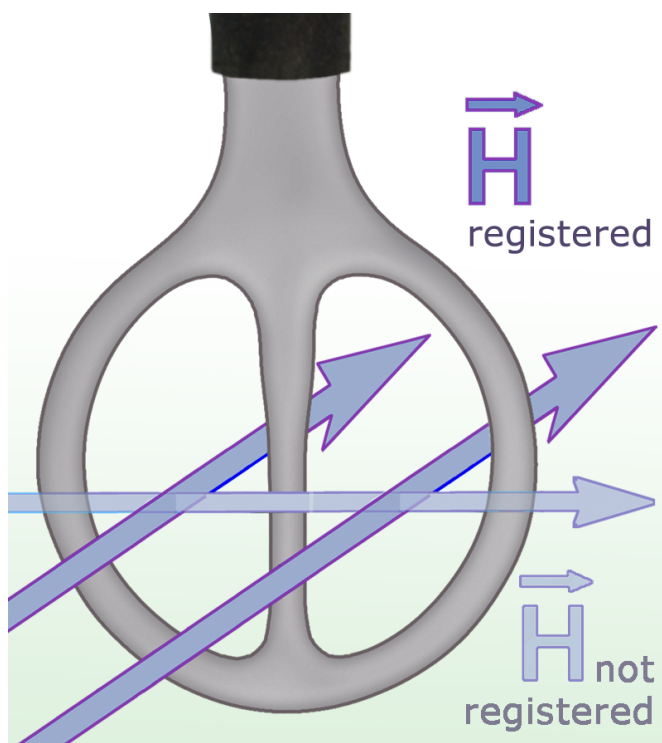


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Measuring principles



Probe head

